



MICROCIRCUIT DATA SHEET

MNDS90LV031A-X REV 1C0

Original Creation Date: 02/09/99
 Last Update Date: 08/15/03
 Last Major Revision Date: 02/21/00

3V LVDS Quad CMOS Differential Line Driver

General Description

The DS90LV031A is a quad CMOS differential line driver utilizing Low Voltage Differential Signaling (LVDS) technology. It is designed for applications requiring low power dissipation and high data rates.

The DS90LV031A accepts TTL/CMOS input levels and translates them to low voltage (350 mV) differential output signals. In addition the driver supports a TRI-STATE function that may be used to disable the output stage, disabling the load current, and thus dropping the device to a low idle power state.

The EN and EN* inputs allow active Low or active High control of the TRI-STATE outputs. The enables are common to all four drivers. The DS90LV031A and companion line receiver (DS90LV032A) provide a new alternative to high power pseudo-ECL devices for high speed point-to-point interface applications.

In addition, the DS90LV031A provides power-off high impedance LVDS outputs. This feature assures minimal loading effect on the LVDS bus lines when VCC is not present.

Industry Part Number

DS90LV031A

Prime Die

DS90LV031A

NS Part Numbers

DS90LV031AW-MLS
 DS90LV031AW-QML
 DS90LV031AWGMLS
 DS90LV031AWGQML

Controlling Document

SEE FEATURES SECTION

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp Description

Temp (°C)

| | | |
|----|---------------------|------|
| 1 | Static tests at | +25 |
| 2 | Static tests at | +125 |
| 3 | Static tests at | -55 |
| 4 | Dynamic tests at | +25 |
| 5 | Dynamic tests at | +125 |
| 6 | Dynamic tests at | -55 |
| 7 | Functional tests at | +25 |
| 8A | Functional tests at | +125 |
| 8B | Functional tests at | -55 |
| 9 | Switching tests at | +25 |
| 10 | Switching tests at | +125 |
| 11 | Switching tests at | -55 |

Features

- High impedance LVDS outputs with power-off
- 3.3V power supply design
- +/- 350mV differential signaling
- Low power dissipation.
- Low differential skew.
- Low propagation delay
- Interoperable with existing 5V LVDS devices
- Military operating temprature range
- Pin compatible with DS26C31.
- Compatible with IEEE 1596.3 SCI LVDS standard
- Compatible with proposed TIA/EIA-644 LVDS standard
- Typical Rise/Fall times of 800pS.
- Typical Tri-State Enable/Disable Delays of less than 5nS.

CONTROLLING DOCUMENT:

| | |
|-----------------|-----------------|
| DS90LV031AW-QML | 5962-9865101QFA |
| DS90LV031AWQML | 5962-9865101QXA |

(Absolute Maximum Ratings)

(Note 1)

| | |
|--|--------------------|
| Supply Voltage (Vcc) | -0.3 to +4V |
| Input Voltage (Din) | -0.3 to (Vcc+0.3V) |
| Enable Input Voltage (EN, EN*) | -0.3 to (Vcc+0.3V) |
| Output Voltage (Dout+, Dout-) | -0.3 to +3.9V |
| Storage Temperature Range | -65C to +150C |
| Lead Temperature Soldering (4 sec) | 260C |
| ESD Rating. | 6000 Volts. |
| Maximum Junction Temperature | +150C |
| Maximum Power Dissipation @ +25C (Note 2) | |
| 16 PIN CERPAK (W Pkg) | 845mW |
| 16 PIN CERAMIC SOIC (WG Pkg) | 845mW |
| Thermal Resistance. (Theta JA) | |
| 16 PIN CERPAK (W Pkg) | 148C/W |
| 16 PIN CERAMIC SOIC (WG Pkg) | 148C/W |
| Thermal Resistance. (Theta JC) | |
| 16 PIN CERPAK (W Pkg) | 22C/W |
| 16 PIN CERAMIC SOIC (WG Pkg) | 22C/W |

Note 1: Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

Note 2: Derate (W & WG Pkgs) at 6.8mW/C for temperatures above +25C.

Recommended Operating Conditions

| | |
|--------------------------------|---------------|
| Supply Voltage | 3.0 to 3.6V |
| Operating Free Air Temperature | -55 to +125 C |

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)

DC: $V_{cc} = 3.0/3.6V$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS |
|--------|---|--|-------|-----------------|-------|-------|------|------------|
| Vod1 | Differential Output Voltage | RL = 100 Ohms | | Dout-, Dout+ | 250 | 450 | mV | 1, 2, 3 |
| DVod1 | Change in Magnitude of Vod1 for complementary output States | RL = 100 Ohms | | Dout-, Dout+ | | 50 | mV | 1, 2, 3 |
| Vos | Offset Voltage | RL = 100 Ohms | | Dout-, Dout+ | 1.125 | 1.625 | V | 1, 2, 3 |
| DVos | Change in Magnitude of Vos for Complementary Output States | RL = 100 Ohms | | Dout-, Dout+ | | 50 | mV | 1, 2, 3 |
| Voh | Output Voltage High | RL = 100 Ohms | | Dout-, Dout+ | | 1.85 | V | 1, 2, 3 |
| Vol | Output Voltage Low | RL = 100 Ohms | | Dout-, Dout+ | .9 | | V | 1, 2, 3 |
| Vih | Input Voltage High | | 1 | Din, EN, EN* | 2.0 | Vcc | V | 1, 2, 3 |
| Vil | Input Voltage Low | | 1 | Din, EN, EN* | Gnd | 0.8 | V | 1, 2, 3 |
| IiH | Input Current | Vin = Vcc or 2.5V, Vcc = 3.6V | | Din, EN, EN* | | ±10 | uA | 1, 2, 3 |
| IiL | Input Current | Vin = Gnd or 0.4V, Vcc = 3.6V | | Din, EN, EN* | | ±10 | uA | 1, 2, 3 |
| Vcl | Input Clamp Voltage | Icl = -8mA, Vcc = 3.0V | | Din, EN, EN* | | -1.5 | V | 1, 2, 3 |
| Ios | Output Short Circuit Current | ENABLED Din = Vcc, Dout+ = 0V or Din = Gnd, Dout- = 0V | | Dout-, Dout+ | | -9.0 | mA | 1, 2, 3 |
| Ioff | Power-off Leakage | Vout = 0V or 3.6V Vcc = 0V or Vcc = Open | | Dout-, Dout+ | | ±20 | uA | 1, 2, 3 |
| Ioz | Output TRI-STATE Current | EN = 0.8V and EN* = 2.0V VOUT = 0V or VCC, VCC = 3.6V | | Dout-, Dout+ | | ±10 | uA | 1, 2, 3 |
| Icc | No Load Drivers Enabled Supply Current | Din = Vcc or Gnd | | Vcc | | 18 | mA | 1, 2, 3 |
| Iccl | Loaded Drivers Enabled Supply Current | RL = 100 ohms All Channels, Din = Vcc or Gnd (all inputs) | | Vcc | | 35 | mA | 1, 2, 3 |
| Iccz | Loaded or No Load Drivers Disabled Supply Current | Din = Vcc or Gnd, En = Gnd, En* = Vcc | | Vcc | | 12 | mA | 1, 2, 3 |

Electrical Characteristics

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)

AC: VCC = 3.0/3.3/3.6V, RL = 100 Ohms, CL = 20pF

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS |
|--------|--|------------|-------|----------|-----|------|------|------------|
| tPHLD | Differential Propagation Delay High to Low | | | | 0.3 | 3.5 | ns | 9, 10, 11 |
| tPLHD | Differential Propagation Delay Low to High | | | | 0.3 | 3.5 | ns | 9, 10, 11 |
| tSKD | Differential Skew tPHLD-tPLHD | | | | | 1.5 | ns | 9, 10, 11 |
| tSK1 | Channel to Channel Skew | | 2 | | | 1.75 | ns | 9, 10, 11 |
| tSK2 | Chip to Chip Skew | | 3 | | | 3.2 | ns | 9, 10, 11 |

Note 1: Tested during VOH/VOL tests.

Note 2: Channel to Channel Skew is defined as the difference between the propagation delay of one channel and that of the others on the same chip with any event on the inputs.

Note 3: Chip to Chip Skew is defined as the difference between the minimum and maximum specified differential propagation delays.

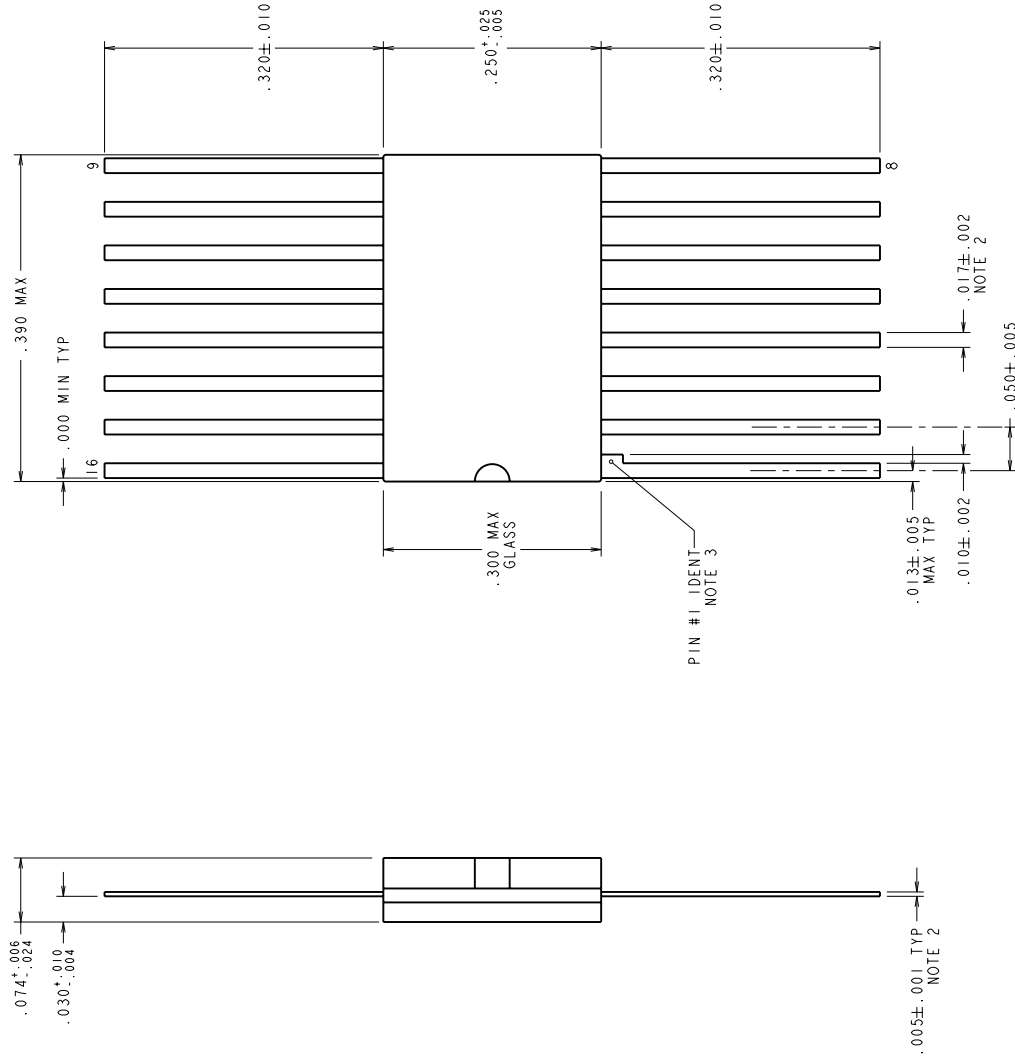
Graphics and Diagrams

| GRAPHICS# | DESCRIPTION |
|-----------|--------------------------------------|
| W16ARL | CERPACK (W), 16 LEAD (P/P DWG) |
| WG16ARC | CERAMIC SOIC (WG), 16 LEAD (P/P DWG) |

See attached graphics following this page.

REVISIONS

| LTR | DESCRIPTION | E.C.N. | DATE | BY/APP'D |
|-----|-------------------------------------|--------|----------|----------|
| K | REVISE AND REDRAW PER NEW STANDARD. | 10514 | 07/28/94 | DEG/AEP |
| L | .017±.002 WAS .017±.020. | 10656 | 10/21/94 | DEG/ |



MIL/AERO
CONFIGURATION CONTROL

MIL-M-38510
CONFIGURATION CONTROL

| APPROVALS | DATE |
|---------------------------|----------|
| DRAWN: <i>D. E. Grady</i> | 07/28/94 |
| DTG. CHK. | |
| ENGR. CHK. | |

National Semiconductor
2900 Semiconductor dr. Santa Clara, CA 95052-8090

CERPACK, 16 LEAD

| SCALE | SIZE | DRAWING NUMBER | REV |
|-------|------|----------------|-----|
| N/A | C | MKT-W16A | L |

DO NOT SCALE DRAWING SHEET 1 of 1

NOTES: UNLESS OTHERWISE SPECIFIED.

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-M-38510 TO A MINIMUM THICKNESS OF 200 MICRONS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE.
- MAXIMUM LIMIT MAY BE INCREASED BY .003 INCHES AFTER LEAD FINISH APPLIED.
- LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
- REFERENCE JEDEC REGISTRATION M0-092, VARIATION AC, DATED 04/89.

Revision History

| Rev | ECN # | Rel Date | Originator | Changes |
|------------|--------------|-----------------|-------------------|--|
| 0A0 | M0003265 | 03/10/00 | Mike Fitzgerald | Initial MDS Release |
| 1A0 | M0003630 | 08/16/02 | Mike Fitzgerald | Added WG pkg NSID's, split out Pkg references under the "Absolute Maximum Ratings" section for Thermal Resistance, and Power Dissipation. Added WG pkg Marketing Outline Drawing. |
| 1B0 | M0004034 | 08/15/03 | Rose Malone | Update MDS: MNDS90LV031A-X, Rev. 1A0 to MNDS90LV031A-X, Rev. 1B0. Added to Main Table NS Part Number DS90LV031AW-MLS. Moved reference to SMD number from Main Table to Features Section. |
| 1C0 | M0004183 | 08/15/03 | Rose Malone | Update MDS: MNDS90LV031A-X, Rev. 1B0 to 1C0. MDS enhancements: Additional verbage to the general discription, Main Table and Added new bullet to the Features Section. |